

| | | | | |
|-----------------------------------|---------------------------------------|--|---------------------------------------------------------------|-------------|
| Notice of References Cited | Application/Control No. 10/594,065 | | Applicant(s)/Patent Under Reexamination TAKEUCHI ET AL. | |
| | Examiner VERNON P. WEBB | | Art Unit 2811 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|----------------|----------------|
| * | A | US-2003/0047737 A1 | 03-2003 | Lin et al. | 257/79 |
| * | B | US-2004/0169184 A1 | 09-2004 | Udagawa et al. | 257/086 |
| * | C | US-7,135,713 B2 | 11-2006 | Chen, Shi-Ming | 257/98 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.